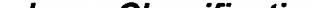


Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/709,762	HSIEH, WEI-JIA
Examiner	Art Unit	
Matthew G. Kayrish	2653	

ORIGINAL				CLASS	CROSS REFERENCE(S)						
CLASS		SUBCLASS			SUBCLASS (ONE SUBCLASS PER BLOCK)						
720		646									
INTERNATIONAL CLASSIFICATION											
G	1	1	B	33/02							
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				/							
Matthew Kayrish (Assistant Examiner) 1/10/2006 (Date)					William Korzuch WILLIAM KORZUCH SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600			Total Claims Allowed: 6			
(Legal Instruments Examiner) (Date)					(Primary Examiner) (Date)			O.G. Print Claim(s)	O.G. Print Fig.		
								1	1		